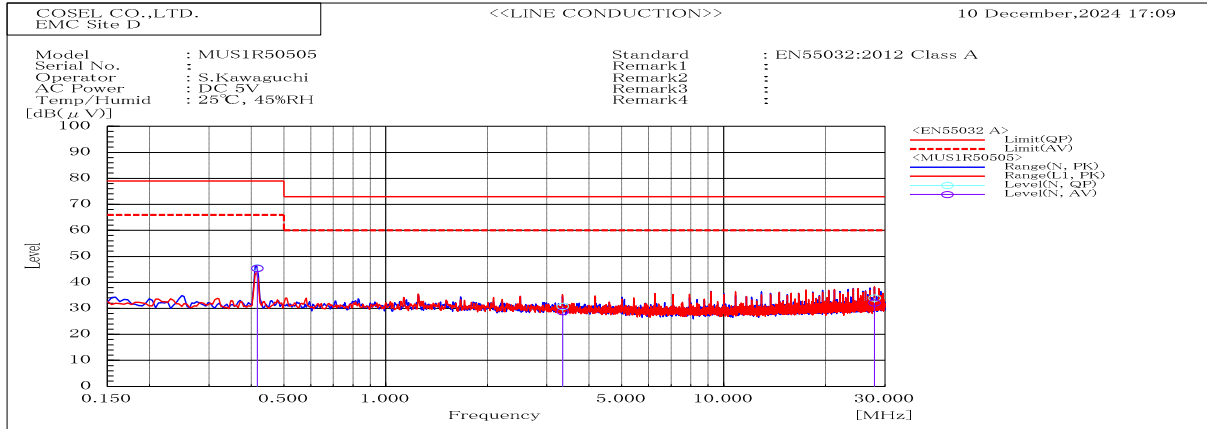
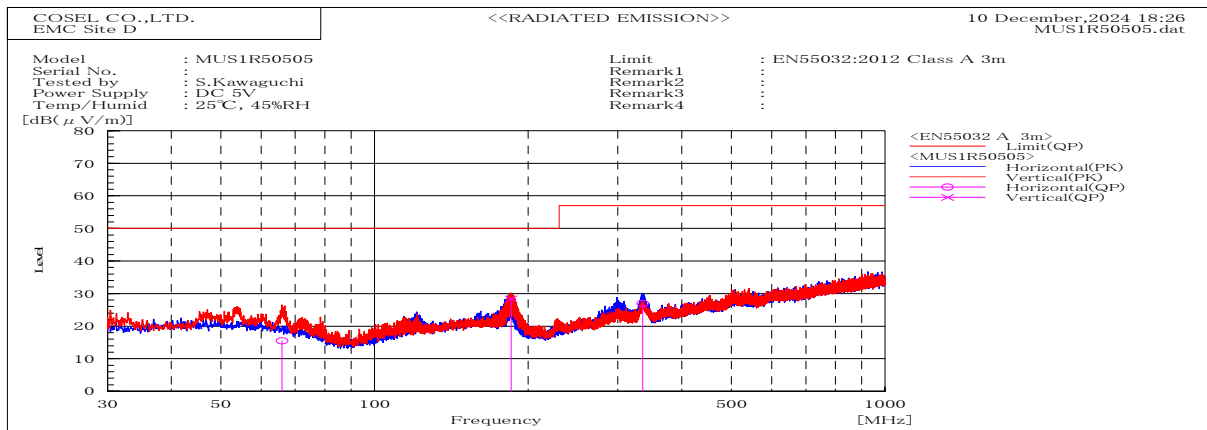


## DATA SHEET

Model		MUS1R50505	Date	05-Mar-25
Test		EMI Line conduction & Radiated emission	Temp.	25 degreeC
			Humid.	45 %RH
			Tested by	S.Kawaguchi



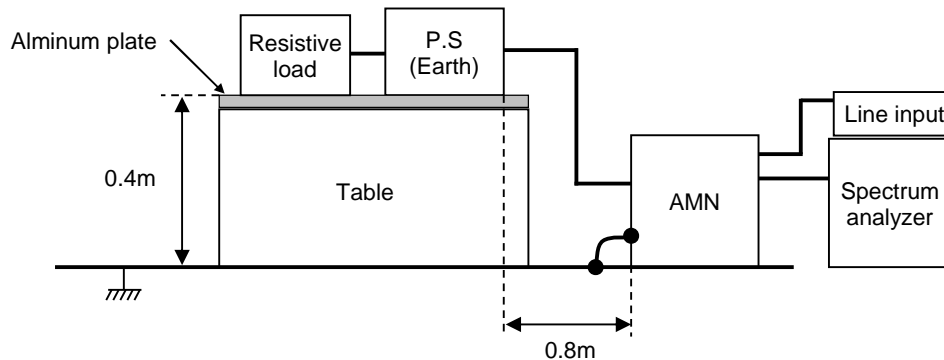
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.417	N	45.6	45.4	79	66	33.4	20.6	Pass	
3.34	N	30.8	28.8	73	60	42.2	31.2	Pass	
27.962	N	34	32.1	73	60	39	27.9	Pass	



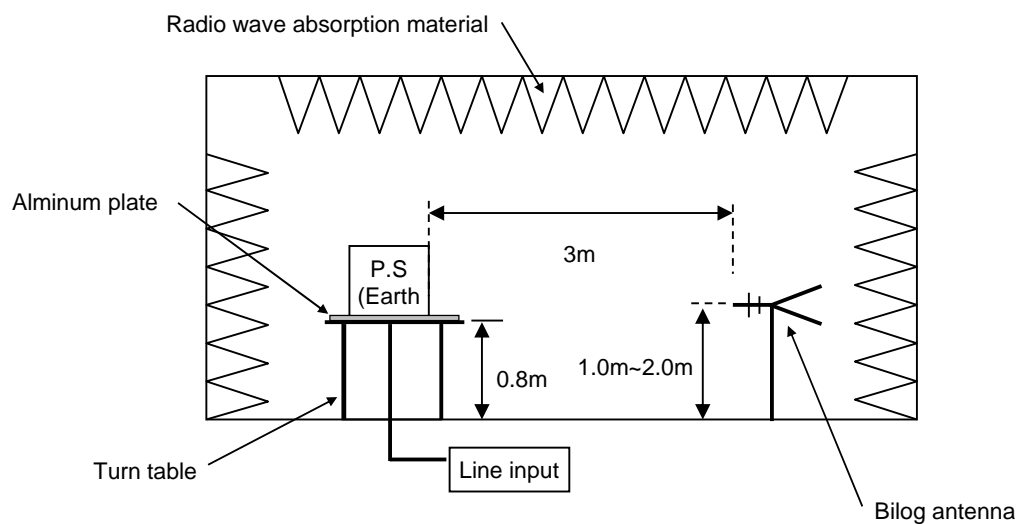
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP		QP				
185.251	V	Stable	28.3	50	21.7	Pass	100	18.1		
65.952	H	Stable	15.5	50	34.5	Pass	100.2	134		
335.334	H	Stable	27	57	30	Pass	100.2	87.1		

DATA SHEET		Date	05-Mar-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

### 1. Line conduction



### 2. Radiated emission



## Conditions

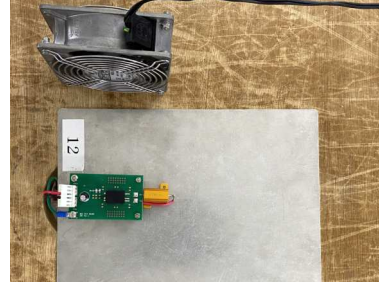
Test : EMI  
Model Name: MUS1R5□□

## ○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



## ○Testing circuitry

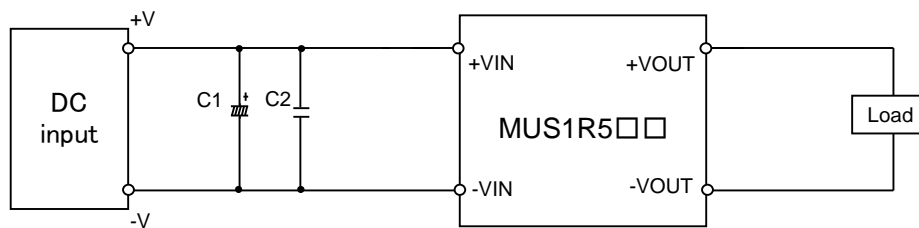


Fig.1 MUS1R505□, MUS1R512□, MUS1R524□ Testing circuitry

C1 :	MUS1R505□	16V 220 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS1R512□	50V 100 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS1R524□	-	
C2 :	MUS1R505□	16V 22 $\mu$ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS1R512□	25V 22 $\mu$ F	Ceramic capacitor (C3216JB1E226MT TDK)
	MUS1R524□	50V 10 $\mu$ F	Ceramic capacitor (C3216X7R1H106KT TDK)

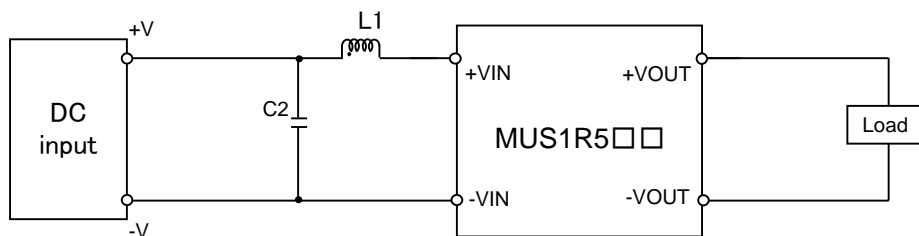


Fig.2 MUS1R548□ Testing circuitry

C2 :	MUS1R548□	100V 2.2 $\mu$ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS1R548□	520mA 15 $\mu$ H	Inductor (LQH32PN150MN0L MURATA MANUFACTURING)